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RAMP 2814

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/054,653 Confirmation No.: 9448
First Named Inventor: Constantin Bulucea Filing Date: January 18, 2002
Group Art Unit: 2814 Examiner: Farahani, D.
Atty. Docket No.: NS-5127 US
Title: Gate-Enhanced Junction Varactor With Gradual Capacitance Variation
Assignee: National Semiconductor Corporation

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INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 CFR 1.56, 1.97, and 1.98, the documents listed on the accompanying substitute PTO Form 1449 are called to the attention of the Examiner for the above patent application. Copies of these documents are enclosed. Further enclosed is an English abstract of Japanese Patent Publication 6-61446.

All of the preceding documents were cited in related U.S. patent application 09/903,059 filed 10 July 2001 and cited in the General Disclosure-of-the-Invention section of the present application.

Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;

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2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in 37 CFR 1.56(b).

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Respectfully submitted,



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U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Application No.
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT O I P E S C A JAN 23 2003 PATENT & TRADEMARK OFFICE		Applicant	Confirmation No.
(Use several sheets if necessary)		Constantin Bulucea	9448
		Filing Date	Group
		January 18, 2002	2814

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,399,893	03/95	Weitzel et al.	257	355	
	AB	5,497,028	03/96	Ikeda et al.	257	531	
	AC	6,100,770	08/00	Litwin et al.	331	117 FE	
	AD	6,166,404	12/00	Imoto et al.	257	279	
	AE						

Foreign Patent Documents

Translation

		Document	Date	Country	Class	Subclass	Yes	No
	AF	6-61446	03/1994	Japan				X
	AG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AH	Andreani, et al., "A 1.8-GHZ CMOS VCO Tuned by an Accumulation-Mode MOS Varactor," <u>IEEE Intl. Symposium on Circuits and Systems</u> , 28 – 31 May 2000, pp. I-315 – I - 318.
AI	Grove, <u>Physics and Technology of Semiconductor Devices</u> (John Wiley & Sons), 1967, pp. 263 – 305.
AJ	Grove, et al., "Effect of Surface Fields on the Breakdown Voltage of Planar Silicon <i>p-n</i> Junction," <u>IEEE Trans. Electron Devices</u> , vol. ED-14 ,1967, pp. 157 – 162.
AK	Grove, et al., "Surface Effects on <i>p-n</i> Junctions: Characteristics of Surface Space-Charge Regions Under Non-Equilibrium Conditions," <u>Solid-State Electronics</u> , Vol. 9, 1966, pp. 783 - 806.
AL	Kral, et al., "RF-CMOS Oscillators with Switched Tuning," <u>Procs. IEEE Custom Integrated Circuits Conference</u> , 1998, pp. 555 – 558.
AM	Lee, <u>The Design of CMOS Radio-Frequency Integrated Circuits</u> (Cambridge Univ. Press), 1998, pp. 37 – 41 and 504 – 514.
AN	McMahon, et al., "Voltage-Sensitive Semiconductor Capacitors," <u>1958 IRE Wescon Conf. Rec.</u> , Part 3, 19 – 22 August 1958, pp. 72 – 82.
AO	Moll, "Variable Capacitance With Large Capacity Change," <u>IRE Wescon Conf. Rec.</u> , Vol. 3, 1959, pp. 32 - 36.

Examiner

Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AF							
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AH	Ng, <u>Complete Guide to Semiconductor Devices</u> (McGraw Hill), 1995, pp. 11 - 22.						
	AI	Razavi, <u>Design of Analog CMOS Integrated Circuits</u> (McGraw Hill), 2001, pp. 495 – 525.						
	AJ	Rusu et al., "Deep-Depletion Breakdown Voltage of Silicon-Dioxide/Silicon MOS Capacitors," <u>IEEE Trans. Elec. Devs.</u> , March 1979, pp. 201 - 205.						
	AK	Rusu et al., "Reversible Breakdown Voltage Collapse in Silicon Gate-Controlled Diodes," <u>Solid-State Electronics</u> , Vol. 23, 1980, pp. 473 - 480.						
	AL	Sedra, et al., <u>Microelectronic Circuits</u> , (4th ed., Oxford Univ. Press), 1998, p. 382.						
	AM	Svelto, et al., "A Three Terminal Varactor for RF IC's in Standard CMOS Technology," <u>IEEE Transactions on Electron Devices</u> , Vol. 47, 2000, pp. 893 – 895.						
	AN	Warner, Jr., et al., <u>Transistors – Fundamentals for the Integrated-Circuit Engineer</u> (John Wiley & Sons), 1983, pp. 320 – 321.						
	AO	Wong et al., "A Wide Tuning Range Gated Varactor," <u>IEEE J. Solid State Circs</u> , May 2000, pp. 773 – 779.						
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